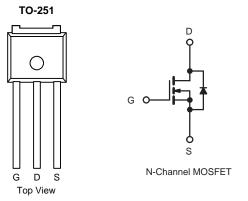


# N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $m\Omega$ )	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)			
30	7 at V <sub>GS</sub> = 10 V	50	19 nC			
	9 at V <sub>GS</sub> = 4.5 V	45	19110			



#### **FEATURES**

- Halogen-free
- TrenchFET® Gen III Power MOSFET
- 100 % R<sub>g</sub> Tested
   100 % UIS Tested

### **APPLICATIONS**

- DC/DC Conversion
  - System Power

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V <sub>DS</sub>	30	V	
Gate-Source Voltage		$V_{GS}$	± 20		
	T <sub>C</sub> = 25 °C		50		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 70 °C	1 ,	45		
Continuous Diain Current (1) = 130 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	14 <sup>b, c</sup>	Α .	
	T <sub>A</sub> = 70 °C		10 <sup>b, c</sup>	A	
Pulsed Drain Current		I <sub>DM</sub>	150		
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	25		
Avalanche Energy	L = 0.111111	E <sub>AS</sub>	40	mJ	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	1.	15	A	
Continuous Source-Diam Diode Current	T <sub>A</sub> = 25 °C	ls ===	2.9 <sup>b, c</sup>	A	
	T <sub>C</sub> = 25 °C		28		
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	18	w	
Waximum Power Dissipation	T <sub>A</sub> = 25 °C	' D	3.5 <sup>b, c</sup>	V V	
	T <sub>A</sub> = 70 °C		2.2 <sup>b, c</sup>		
Operating Junction and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C		
Soldering Recommendations (Peak Tempera	-	260			

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient	t ≤ 10 s	$R_{thJA}$	29	36	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	3.6	4.5	7		

- a. Based on T<sub>C</sub> = 25 °C.
  b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.



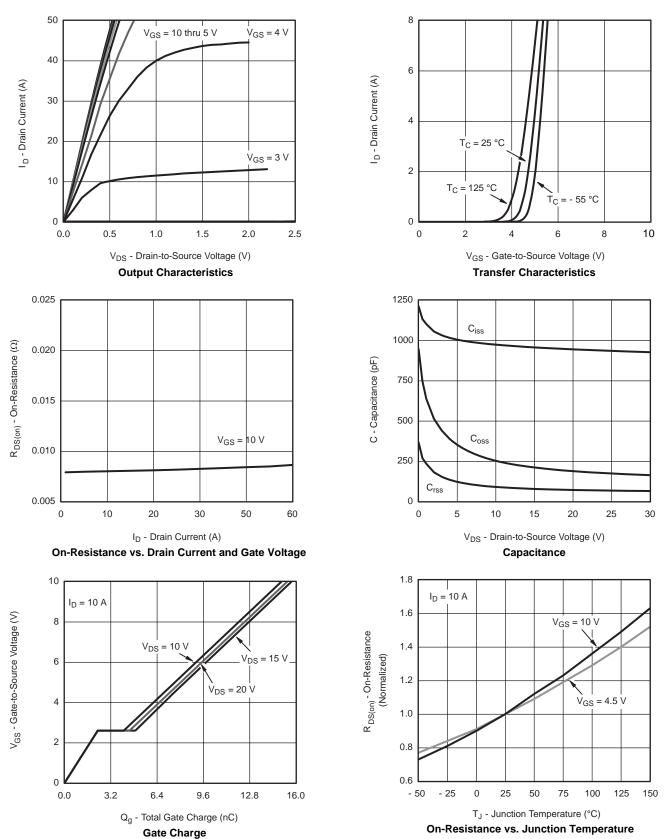
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static				•	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			33		m\//º(
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 5		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_{D} = 250 \mu A$	1.2		3.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Cata Valtana Duais Comunit	I <sub>DSS</sub>	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			5	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	15			Α
Dunin Course On Otata Basistanas		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A	7			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 7 \text{ A}$		9		mΩ
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 10 A		24		S
Dynamic <sup>b</sup>			,	•		<u>I</u>
Input Capacitance	C <sub>iss</sub>			1700		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		200		
Reverse Transfer Capacitance	C <sub>rss</sub>			150		
Total Oata Ohanna		V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		33		
Total Gate Charge				18		
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		7.3		nC
Gate-Drain Charge	Q <sub>gd</sub>			6.2		
Gate Resistance	$R_g$	f = 1 MHz	0.2	0.8	1.6	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			15	30	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 1.5 $\Omega$		12	24	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong$ 10 A, $V_{GEN}$ = 4.5 V, $R_g$ = 1 $\Omega$		13	26	
Fall Time	t <sub>f</sub>			10	20	
Turn-On Delay Time	t <sub>d(on)</sub>			9	18	ns
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 1.5 $\Omega$		9	18	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 10$ A, $V_{GEN}=10$ V, $R_g=1$ $\Omega$		14	28	
Fall Time	t <sub>f</sub>			8	16	
<b>Drain-Source Body Diode Characteristi</b>	cs					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			16	۸
Pulse Diode Forward Current	I <sub>SM</sub>				32	Α
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 3 A, V <sub>GS</sub> = 0 V		0.78	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			17	34	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$	I <sub>F</sub> = 10 A, dl/dt = 100 A/μs, T <sub>.I</sub> = 25 °C		9.5	19	nC
Reverse Recovery Fall Time	t <sub>a</sub>	i <sub>F</sub> = 10 A, αίναι = 100 Ανμ5, 1 <sub>J</sub> = 25 °C		10		
everse Recovery Rise Time t <sub>b</sub>				7		ns

#### Notes:

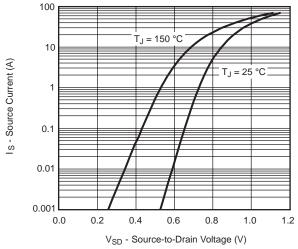
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

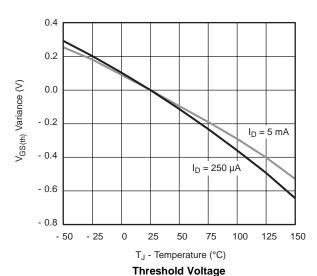








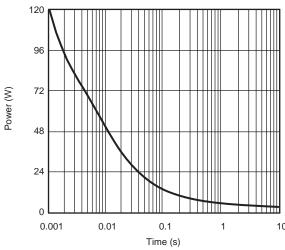
#### Source-Drain Diode Forward Voltage



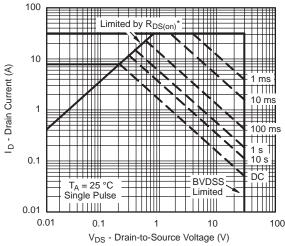
0.06  $I_D = 10^{\circ} A$ 0.05  $R_{DS(on)}$  - On-Resistance ( $\Omega$ ) 0.04 0.03  $T_J = 125$  °C 0.02 0.01  $T_J = 25 \, ^{\circ}C$ 0.00 2 3 0 4 5

V<sub>GS</sub> - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



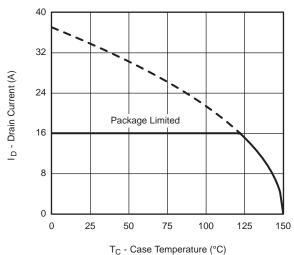
Single Pulse Power (Junction-to-Ambient)



\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

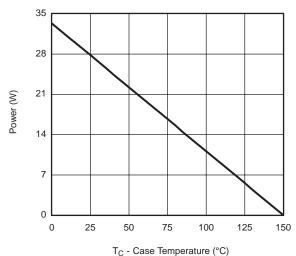
Safe Operating Area, Junction-to-Ambient

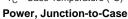


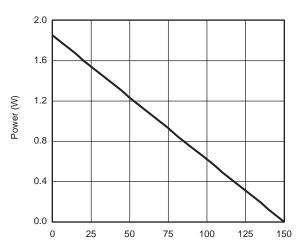


Current Dereting\*

### **Current Derating\***





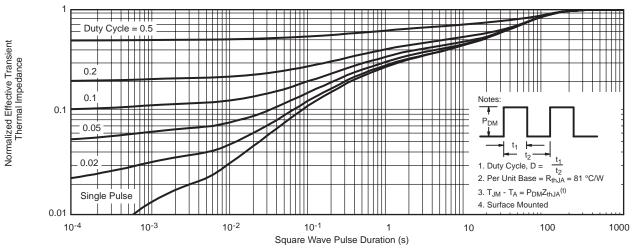


T<sub>A</sub> - Case Temperature (°C)

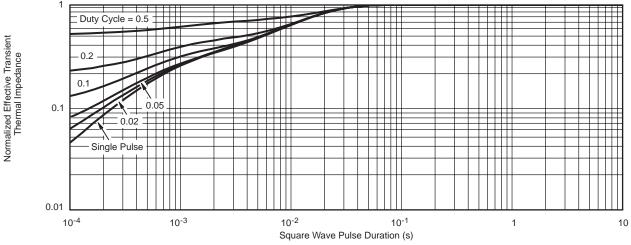
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





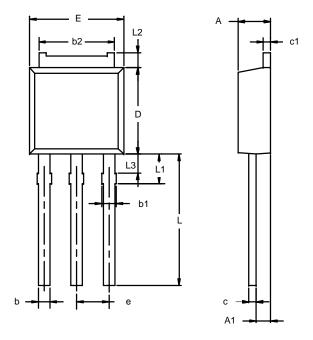
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



## TO-251AA (DPAK)



Note: Dimension L3 is for reference only.

	MILLIM	IETERS	INC	HES	
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
E	6.48	6.73	0.255	0.265	
е	2.28	BSC	0.090 BSC		
L	3.89	9.53	0.153	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346					



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DMN2080UCB4-7 DMN61D9UWQ-13 US6M2GTR DMN31D5UDJ-7 DMP22D4UFO-7B DMN1006UCA6-7 DMN16M9UCA6-7
STF5N65M6 IRF40H233XTMA1 STU5N65M6 DMN6022SSD-13 DMN13M9UCA6-7 DMTH10H4M6SPS-13 DMN2990UFB-7B
IPB80P04P405ATMA2 2N7002W-G MCAC30N06Y-TP MCQ7328-TP BXP7N65D BXP4N65F AOL1454G WMJ80N60C4 BXP2N20L
BXP2N65D BXT1150N10J BXT1700P06M TSM60NB380CP ROG RQ7L055BGTCR DMNH15H110SK3-13 SLF10N65ABV2
BSO203SP BSO211P IPA60R230P6 IPA60R460CE